

(12) INTERNATIONAL APPLICATION PUBLISHED UNDER THE PATENT COOPERATION TREATY (PCT)

(19) World Intellectual Property
Organization
International Bureau



542873

(43) International Publication Date
19 August 2004 (19.08.2004)

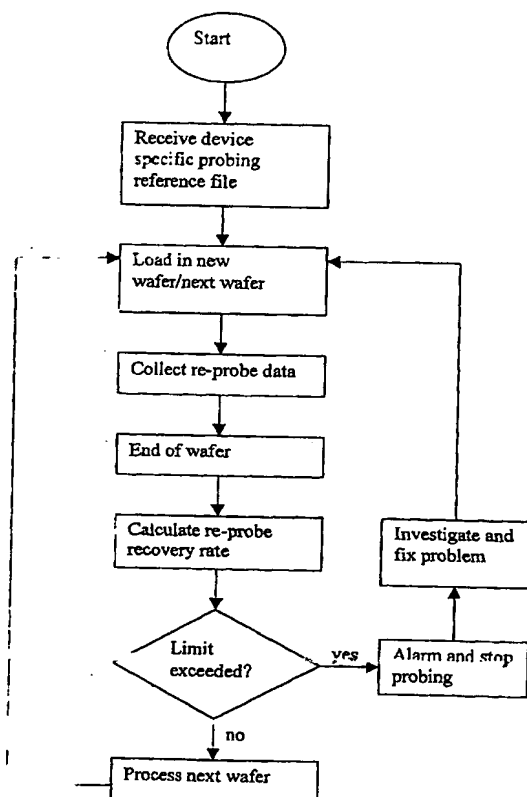
PCT

(10) International Publication Number
WO 2004/070399 A1

- (51) International Patent Classification⁷: **G01R 1/067**, 31/02
- (21) International Application Number: PCT/SG2003/000022
- (22) International Filing Date: 5 February 2003 (05.02.2003)
- (25) Filing Language: English
- (26) Publication Language: English
- (71) Applicant (for all designated States except US): **SYS-TEMS ON SILICON MANUFACTURING CO. PTE. LTD.** [SG/SG]; 70 Pasir Ris Drive 1, Singapore 519527 (SG).
- (72) Inventor; and
- (75) Inventor/Applicant (for US only): **TAN, Beng, Ghee** [SG/SG]; Blk 872 Tampine St. 84, #10-87, Singapore 520874 (SG).
- (74) Agent: **DREW & NAPIER LLC**; 20 Raffles Place, #17-00, Ocean Towers, Singapore 048620 (SG).
- (81) Designated States (national): AE, AG, AL, AM, AT, AU, AZ, BA, BB, BG, BR, BY, BZ, CA, CH, CN, CO, CR, CU, CZ, DE, DK, DM, DZ, EC, EE, ES, FI, GB, GD, GE, GH, GM, HR, HU, ID, IL, IN, IS, JP, KE, KG, KP, KR, KZ, LC, LK, LR, LS, LT, LU, LV, MA, MD, MG, MK, MN, MW, MX, MZ, NO, NZ, OM, PH, PL, PT, RO, RU, SC, SD, SE, SG, SK, SL, TJ, TM, TN, TR, TT, TZ, UA, UG, US, UZ, VC, VN, YU, ZA, ZM, ZW.
- (84) Designated States (regional): ARIPO patent (GH, GM, KE, LS, MW, MZ, SD, SL, SZ, TZ, UG, ZM, ZW), Eurasian patent (AM, AZ, BY, KG, KZ, MD, RU, TJ, TM), European patent (AT, BE, BG, CH, CY, CZ, DE, DK, EE, ES, FI, FR, GB, GR, HU, IE, IT, LU, MC, NL, PT, SE, SI, SK, TR), OAPI patent (BF, BJ, CF, CG, CI, CM, GA, GN, GQ, GW, ML, MR, NE, SN, TD, TG).
- Published:
— with international search report

[Continued on next page]

(54) Title: A METHOD FOR DETECTING AND MONITORING WAFER PROBING PROCESS INSTABILITY



(57) Abstract: A system and method for detecting and monitoring wafer probe stability including the steps of, probing each die on a wafer, and for each die determining whether the result of the probe is a pass or a fail. If the result of a probe is a fail, re-probing the die and determining whether the re-probe is a pass or a fail. Once all the dies have been probed determining the rate of die re-probes that lead to passes, comparing the rate of passes on re-probes to a pre-determined limit, and if the rate of passes on re-probes is greater than the predetermined limit, assigning the probe status as unstable.

WO 2004/070399 A1



For two-letter codes and other abbreviations, refer to the "Guidance Notes on Codes and Abbreviations" appearing at the beginning of each regular issue of the PCT Gazette.